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Application No. 10/047,550	Prepared by	BZM	Tracking Number	05931458
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a. Serial No.	f. Foreign Priority	k. Print Claim(s)	(P.) PTO-1449		
b. Applicant(s)	g. Disclaimer	I. Print Fig.	q. PTOL-85b		
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract		
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs		
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other		

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Attorney Docket No: SLM-06100

1 2	6.	(original) The method of claim 2, wherein the conductive layer further comprises a metal deposited onto the conductive polymer.
1	7.	(currently amended) The method of claim 1, wherein the selected portions of the
2		conductive layer on the top surface of the Ferroelectric ferroelectric material are selected
3		by patterning the conductive layer on the top surface of the Ferroelectric ferroelectric
4		material.
1	8.	(currently amended) The method of claim 7, wherein the conductive layer on the top
2		surface of the Ferroelectric ferroelectric material is patterned by:
3		a. forming a mask over the conductive layer on the top surface of the Ferroelectric
4		ferroelectric material;
5		b. selectively removing the exposed portion of the conductive layer on the top
6		surface of the Ferroelectric ferroelectric material; and
7		c. removing the mask.
1	9.	(original) The method of claim 8, wherein the mask is formed from a photo-resist.
1	10.	(currently amended) The method of claim 9, wherein the mask is formed by:
2		a. depositing the photo-resist on the conductive layer on the top surface of the
3		Ferroelectric ferroelectric material;
4		b. exposing areas of the photo-resist with a light source according to a predetermined
5		pattern; and
6		c. developing the photo-resist to remove the unexposed portions of the photo-resist.
1	11.	(currently amended) The method of claim 1, further comprising the steps of placing the
2		conductive layer on the top surface of the Ferroelectric ferroelectric material and the
3		conductive layer on the bottom surface of the Ferroelectric ferroelectric material in
4		electrical communication.
1	12.	(currently amended) The method of claim 11, wherein the step of placing the conductive

layer on the top surface of the Ferroelectric ferroelectric material and the conductive layer

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Sheet 2 of 7

FORM PTO-1449 (Modified)

(37 CFR § 1.98(b))

U.S. Department of Commerce Patent and Trademark Office

Attorney Docket No.: SLM-06100

Serial No.: 10/047,550

U.S. Department of Copartment and Trademark (Information disclosure Statement By Applicant (Use System Sheets If Necessary)

Applicants: Gregory D. Miller et al

Filing Date: January 15, 2002

Group Art Unit; 2881- 1731

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1	INFORMATION DESCLOSURE STATEMENT BY APPLICANT Applicants: Gregory D. Miller et al								
(37 CFR § 1.5	(37 CFR § 1.98(b))  Filing Date: January 15, 2002 Group Art Unit-288			it: <del>2881</del> /	1731				
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FORM PTO-1 (Modified)	449	JUL 7 4 2003 U.S. Department of Commerce Patent and Trademark Office	Attorney Docket No.: SLM-06100	Serial No.: 10/04/150			
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